GSM3112DF

30V N-Channel MOSFETs

Product Description

These N-Channel enhancement mode power field effect transistors are using trench DMOS technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode.

These devices are well suited for high efficiency fast switching applications.

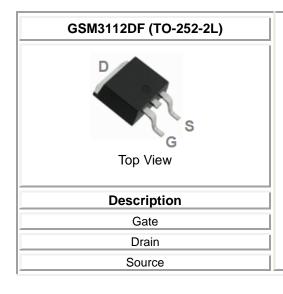
Features

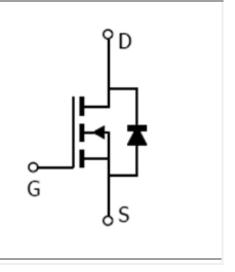
- 30V, 40A, $R_{DS(ON)}=12m\Omega@V_{GS}=10V$
- Improved dv/dt capability
- Fast switching
- 100% EAS guaranteed
- Green Device Available

Applications

- MB / VGA / Vcore
- DC-DC Converters
- Power Management Functions

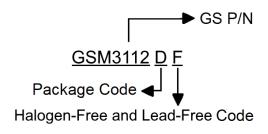
Packages & Pin Assignments





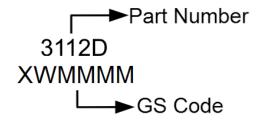


Ordering Information



Part Number	Package	Quantity
GSM3112DF	TO-252	2500pcs

Marking Information



Absolute Maximum Ratings Tc=25°C Unless otherwise noted

Symbol	Parameter		Typical	Unit
V _{DS}	Drain-Source Voltage		30	V
V _G s	Gate-Source Voltage		±20	V
		T _A =25°C	40	
ID	Continuous Drain Current	T _A =70°C	30	Α
		Tc=25°C	11.8	
I _{DM}	Pulsed Drain Current ¹		50	А
EAS	Single Pulse Avalanche Energy ²		13	mJ
	Power Dissipation	T _A =25°C	2.5	
PD		T _A =70°C	1.6	W
		T _C =25°C	40.3	
TJ	Operating Junction Temperature Range		-55 to +150	°C
T _{STG}	Storage Temperature Range		-55 to +150	$^{\circ}\mathbb{C}$
R _{0JA}	Thermal Resistance-Junction to Ambient		50	°C/W
R _{eJC}	Thermal Resistance-Junction to Case		3.1	°C/W



Electrical Characteristics

T_J=25°C Unless otherwise noted

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
		Static				
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D =250uA	30			V
$V_{GS(th)}$	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =250uA	1.2		2.5	V
I _{GSS}	Gate-Source Leakage Current	V _{DS} =0V, V _{GS} =±20V			±100	nA
I _{DSS}	Drain-Source Leakage Current	V _{DS} =30V, V _{GS} =0V			1	uA
	Durin Course On Besisters 3	V _{GS} =10V, I _D =10A		9.8	12	
R _{DS(on)}	Drain-Source On-Resistance ³	V _{GS} =4.5V, I _D =5A,		15.7	18	mΩ
g FS	Forward Transconductance	V _{DS} =10V, I _D =3A			10	S
V _{SD}	Diode Forward Voltage ³	V _{GS} =0V, I _S =1A		0.7	1	V
		Dynamic				
Qg	Total Gate Charge ^{3,4}			8		nC
Q _{gs}	Gate-Source Charge ^{3,4}	V _{DS} =15V, V _{GS} =4.5V, I _D =12.5A		4		
Q_{gd}	Gate-Drain Charge ^{3,4}	ID=12.5A		2		
Ciss	Input Capacitance			1040		
Coss	Output Capacitance	V _{DS} =15V,V _{GS} =0V, f=1MHz		445		pF
Crss	Reverse Transfer Capacitance	1=111112		40		Ī <u>L</u>
t _{d(on)}	Turn-On Time ^{3,4}			10		
tr	Rise Time ^{3,4}	V _{DD} =15V, I _D =12.5A,		9		İ
t _{d(off)}	Turn-Off Time ^{3,4}	V _{GS} =10V, R _G =6Ω		24		ns
t _f	Fall Time ^{3,4}			8		
Rg	Gate Resistance	V _{GS} =0V, V _{DS} =0V, f=1MHz		1.1		Ω

Note:

- 1. Repetitive Rating : Pulsed width limited by maximum junction temperature.
- 2. V_{DD} =15V, V_{GS} =10V, L=0.1mH, I_{AS} =13A, Starting T_J =25 $^{\circ}$ C.
- 3. The data tested by pulsed , pulse width $\,\leq\,\,$ 300us , duty cycle $\,\leq\,\,$ 2%.
- 4. Essentially independent of operating temperature.



Typical Performance Characteristics

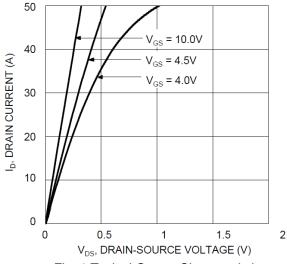


Fig. 1 Typical Output Characteristics

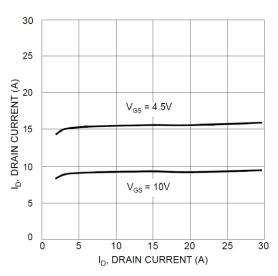


Fig. 3 Typical On-Resistance vs I_{D} and V_{GS}

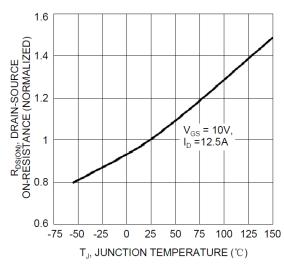


Figure. 5 On-Resistance Variation with TJ

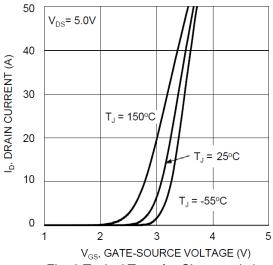


Fig. 2 Typical Transfer Characteristics

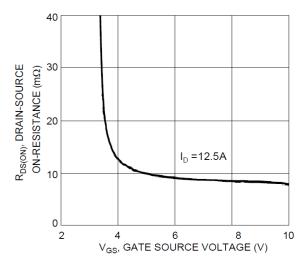


Fig. 4 Typical Transfer Characteristic

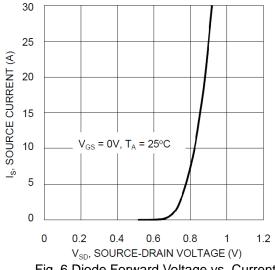


Fig. 6 Diode Forward Voltage vs. Current

Typical Performance Characteristics (Continue)

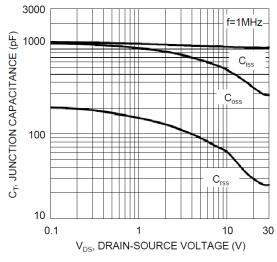


Fig. 7 Typical Capacitance

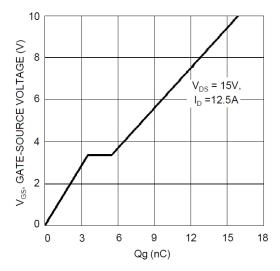
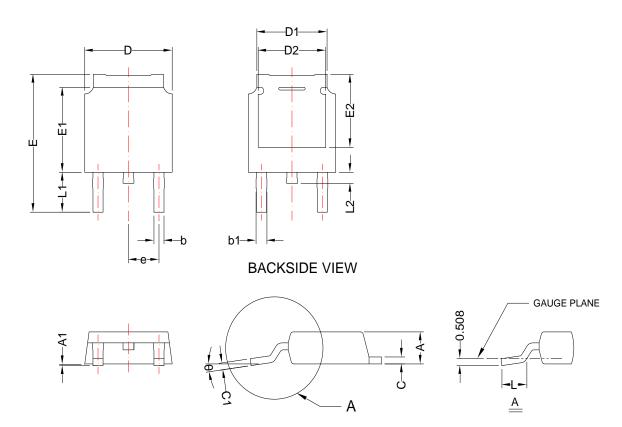


Fig. 8 Gate Charge



Package Dimension

TO-252(AA)



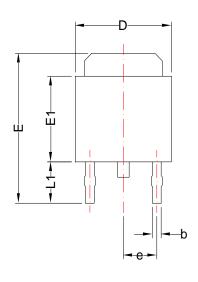
THE PACKAGE TOP MAY BE SMALLER THAN THE PACKAGE BOTTOM. DIMENDIONS D AND E ARE DETERMINED AT THE OUTERMOST EXTREMS OF THE PLASTIC BODY EXCLUSIVE OF MOLD FLASH, TIE BAR BURSS, GATE BURS AND INTETLEAD FLASH, BUT INCLUDING ANY MISMATCH BETWEEN THE TOP AND BOTTOM OF THE PLASTIC BODY.

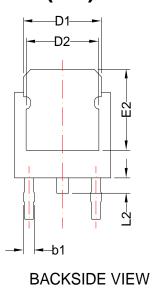
DIMENSION D DOES NOT INCLUDE INTERLEAD FLASH OR PROTRUSION. INTERLEAD FLASH OR PROTRUSION SHALL NOT EXCEED 0.15mm PER DNE. DIMENSION E1 DOES NOT INCLUDE MOLD FLASH, PROTRUSION. OR GATE BURRS. MOLD FLASH, PROTRUSIONS OR GATE BURRS SHALL EXCEED 0.15mm INCHES PER DNE.

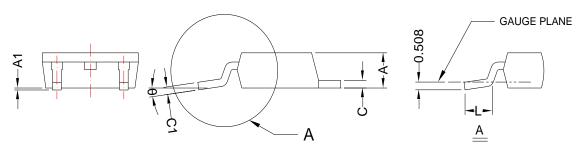
	Dimensions				
	Millimeters		Inches		
Symbol	Min	Мах	Min	Max	
Α	2.18	2.40	0.086	0.094	
A 1	0.00	0.15	0.000	0.006	
b	0.64	0.90	0.025	0.035	
b1	0.76	1.14	0.030	0.045	
С	0.40	0.89	0.016	0.035	
c1	0.40	0.61	0.016	0.024	
D	6.35	6.73	0.250	0.265	
D1	4.95	5.46	0.195	0.215	
D2	4.32		0.170		



TO-252(AB)







DIMENSION D DOES NOT INCLUDE INTERLEAD FLASH OR PROTRUSION. INTERLEAD FLASH OR PROTRUSION SHALL NOT EXCEED 0.15mm PER DNE. DIMENSION E1 DOES NOT INCLUDE MOLD FLASH, PROTRUSION. OR GATE BURRS. MOLD FLASH, PROTRUSIONS OR GATE BURRS SHALL EXCEED 0.15mm INCHES PER DNE.

Dimensions					
Complete	Millimeters		Inches		
Symbol	Min	Max	Min	Max	
Α	2.18	2.40	0.086	0.094	
A 1	0.00	0.15	0.000	0.006	
b	0.50	0.90	0.020	0.035	
b1	0.60	1.14	0.024	0.045	
С	0.45	0.89	0.018	0.035	
c1	0.40	0.61	0.016	0.024	
D	6.35	6.80	0.250	0.268	
D1	4.95	5.50	0.195	0.217	
D2	3.81		0.150		



E	9.40	10.41	0.370	0.410	
E1	5.33	5.80	0.210	0.228	
E2	4.57		0.180		
e	2.286 BSC		0.090 BSC		
L	1.40	1.78	0.055	0.070	
L1	2.40	3.00	0.094	0.118	
L2		1.20		0.047	
θ	0°	8°	0°	8°	



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